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REISSUE PATENT APPLICATION TRANSMITTAL

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First Named Inventor	Peter B. Gillingham
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APPLICATION FOR REISSUE OF:

 Utility Patent Design Patent Plant Patent

(Check applicable box)

Title of Invention

METHOD OF MULTI-LEVEL STORAGE IN DRAM AND APPARATUS THEREOF (As Amended)

APPLICATION ELEMENTS		ACCOMPANYING APPLICATION PARTS	
1. <input checked="" type="checkbox"/> Fee Transmittal Form <i>(Submit an original, and a duplicate for fee processing)</i>		7. <input type="checkbox"/> Transfer drawings from Patent File	
2. <input checked="" type="checkbox"/> Specification and Claims (amended, if appropriate)		8. <input type="checkbox"/> Foreign Priority Claim (35 U.S.C. 119) <i>(if applicable)</i>	
3. <input checked="" type="checkbox"/> Drawing(s) (proposed amendments, if appropriate)		9. <input checked="" type="checkbox"/> Information Disclosure Statement (IDS)/PTO-1449 <input type="checkbox"/> Copies of IDS Citations	
4. <input checked="" type="checkbox"/> Reissue Oath / Declaration (original or copy) / POA <i>(37 C.F.R. 1.175)</i>		10. <input type="checkbox"/> English Translation of Reissue Oath / Declaration <i>(if applicable)</i>	
5. <input type="checkbox"/> Original U.S. Patent		11. <input type="checkbox"/> Small Entity Statement(s) <input type="checkbox"/> Statement filed in prior application, Status still proper and desired	
<input type="checkbox"/> Offer to Surrender Original Patent (37 C.F.R. 1.178) or <input type="checkbox"/> Ribboned Original Patent Grant		12. <input type="checkbox"/> Preliminary Amendment	
<input type="checkbox"/> Affidavit / Declaration of Loss		13. <input checked="" type="checkbox"/> Return Receipt Postcard (MPEP 503) (2) <i>(Should be specifically itemized)</i>	
6. <input checked="" type="checkbox"/> Original U.S. Patent currently assigned? <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No <i>(If Yes, check applicable box(es))</i>		14. <input checked="" type="checkbox"/> This is a broadening Reissue, broadened claim(s) included (within 2 years of issue date)	
<input type="checkbox"/> Written Consent of all Assignees		15. <input type="checkbox"/> Other:	
<input type="checkbox"/> 37 C.F.R. 3.73(b) Statement <input type="checkbox"/> Power of Attorney			

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JMS/GMB/dlc
08/18/00PATENT APPLICATION
Docket No.: 2037.1005-002

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

JC639 U.S. PTO
09/09/654367
09/01/00

Applicant: Peter B. Gillingham

Reissue Application of U.S. Patent 5,283,761, Issued February 1, 1994

For: METHOD OF MULTI-LEVEL STORAGE IN DRAM AND APPARATUS THEREOF (as amended)

Date: 8/27/00 9-1-00EXPRESS MAIL LABEL NO. E1551544795USWRITTEN CONSENT OF ASSIGNEE IN CONTINUATION
OF REISSUE APPLICATIONAssistant Commissioner for Patents
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Sir:

Mosaid Technologies Incorporated is the assignee of the referenced patent application and does hereby consent to the referenced continuation of reissue patent application.

A Certificate under 37 C.F.R. §3.73(b) certifying that, to the best of my knowledge and belief, title is in Mosaid Technologies Incorporated is being filed concurrently with this Written Consent.

Respectfully submitted,

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Date: 21 August 2000

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REISSUE APPLICATION FEE TRANSMITTAL FORM

Docket Number (Optional)

2037.1005-002

Claims as Filed - Part 1

Claims in Patent	For	Number Filed in Reissue Application	(3) Number Extra	Small Entity		Other than a Small Entity	
				Rate	Fee	Rate	Fee
(A) 41	Total Claims (37 CFR 1.16(j))	(B) 10	**** 0 = x \$ _____ =			x \$ _____ =	0
(C) 9	Independent Claims (37 CFR 1.16(i))	(D) 2	* 0 = x \$ _____ =			x \$ _____ =	0
Basic Fee (37 CFR 1.16(h))				\$ _____			\$ 690
Total Filing Fee				\$ _____	OR		\$ 690

Claims as Amended - Part 2

	(1) Claims Remaining After Amendment		(2) Highest Number Previously Paid For	(3) Extra Claims Present	Small Entity		Other than a Small Entity	
					Rate	Fee	Rate	Fee
Total Claims (37 CFR 1.16(j))	***	MINUS	**	*	x \$ _____ =		x \$ _____ =	
Independent Claims (37 CFR 1.16(i))	***	MINUS	*****	=	x \$ _____ =		x \$ _____ =	
Total Additional Fee				\$ _____		OR		\$ _____

* If the entry in (D) is less than the entry in (C), Write "0" in column 3.

** If the "Highest Number of Total Claims Previously Paid For" is less than 20, Write "20" in this space.

*** After any cancelation of claims

**** If "A" is greater than 20, use (B - A); if "A" is 20 or less, use (B - 20).

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8/29/00Duly 2 M 44,075

Signature of Applicant, Attorney or Agent of Record

Gerald M. Bluhm

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REISSUE APPLICATION FEE TRANSMITTAL FORM					Docket Number (Optional) 2037.1005-002		
Claims as Filed - Part 1							
Claims in Patent	For	Number Filed in Reissue Application	(3) Number Extra	Small Entity	Other than a Small Entity		
(A) 41	Total Claims (37 CFR 1.16(j))	(B) 10	**** 0 = x \$ ____ =	or	x \$ ____ =	0	
(C) 9	Independent Claims (37 CFR 1.16(i))	(D) 2	* 0 = x \$ ____ =	x \$ ____ = 0			
Basic Fee (37 CFR 1.16(h))				\$ _____			
Total Filing Fee				\$ _____			
Claims as Amended - Part 2							
	(1) Claims Remaining After Amendment	(2) Highest Number Previously Paid For	(3) Extra Claims Present	Small Entity	Other than a Small Entity		
Total Claims (37 CFR 1.16(j))	***	MINUS	** * = x \$ ____ =	or	x \$ ____ =		
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<p><small>* If the entry in (D) is less than the entry in (C), Write "0" in column 3.</small></p> <p><small>** If the "Highest Number of Total Claims Previously Paid For" is less than 20, Write "20" in this space.</small></p> <p><small>*** After any cancelation of claims</small></p> <p><small>**** If "A" is greater than 20, use (B - A); if "A" is 20 or less, use (B - 20).</small></p> <p><small>***** "Highest Number of Independent Claims Previously Paid For" or Number of Independent Claims in Patent (C).</small></p>							
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<u>8/29/00</u> Date				<u>Duly 2 JLL</u> <u>44,075</u> Signature of Applicant, Attorney or Agent of Record			
<u>Gerald M. Bluhm</u> Typed or printed name							

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METHOD OF MULTI-LEVEL STORAGE IN DRAM

This is a continuation of Reissue Application Ser. No. 08/595,020, filed January 31, 1996, which is based on original U.S. Pat. No. 5,283,761 issued February 1, 1994.

FIELD OF THE INVENTION

This invention relates to dynamic random access memory (DRAM) memories, and in particular to a method of storing a variable level signal in each cell of a DRAM for representing more than one bit in each cell.

BACKGROUND TO THE INVENTION

To store for example two bits in a DRAM cell, it must be able to store four different voltage levels. A problem with such cells, is that noise margins are reduced to one-third that of a one bit per cell DRAM, which is too low to withstand the occasional α -particle hit.

A second problem with multi-bit storage cells relates to the method of sensing. No simple method of sensing has previously been designed, although attempts have been made to solve this problem, e.g. as described in the publication by M. Aoki et al, "A 16-Levels/Cell Dynamic Memory", ISSCC Dig. TECH. Papers 1985, pp 246-247, and in T. Furuyama et al, "An Experimental Two-Bit/Cell Storage DRAM for Macrocell or Memory-On-Application", IEEE Journal of Solid State Circuits, Vol. 24, No. 2, pp. 388-393, April 1989. The technique described by Aoki cannot use normal sense amplifiers. It requires a precision analog D to A converter to implement a staircase waveform and a charge amplifier to sense data. The technique described by Furuyama requires the generation of precision reference levels to distinguish between four levels. These levels are not self-compensated for offsets developed in the sensing operation, and this method suffers from poor signal margin. Hidaka et al describe a technique for simultaneously reading two cells at a time in the article "A divided/Shared Bitline Sensing Scheme for .64Mb DRAM Core" in the 1990 Symposium on VLSI Circuitry 1990, IEEE, p. 15, 16 which while describing dividing a bitline, is not related to multiple bit storage in a single cell.

DRAMs have previously been built with cells holding up to sixteen bits of storage, e.g. in the aforementioned article by M. Aoki et al, for use in file memories. A 4 K test array is believed to have been the largest memory built using this design. Leakage characteristics of the DRAM cell were required to be very tightly controlled and even then, accurate sensing of the small voltage differences between levels becomes very difficult. Another problem with this scheme was the length of time required to access: a single read cycle required 16 clocks for the read followed by 16 clocks for the restore.

To implement a 2 bit DRAM, one can define the cell as storing one of four voltage levels V_{cell0} , V_{cell1} , V_{cell2} and V_{cell3} , and reference voltage midpoints between these four voltage, which can be defined as V_{ref1} , V_{ref2} and V_{ref3} . These midpoints can be referred to, to differentiate between the four voltage levels. The relative voltage of these levels are shown in Table I below.

STORAGE VOLTAGES	REFERENCE VOLTAGES	ACTUAL VOLTAGE
V_{cell1}	V_{ref3}	V_{DD}
V_{cell2}		$5/6 V_{DD}$
		$2/3 V_{DD}$

-continued

STORAGE VOLTAGES	REFERENCE VOLTAGES	ACTUAL VOLTAGE
V_{cell1}	V_{ref2}	$1/2 V_{DD}$ $1/3 V_{DD}$
V_{cell0}	V_{ref1}	$1/6 V_{DD}$ V_{SS}

The storage voltages are the actual voltages stored in the cells, although the sensing voltages are somewhat more attenuated. Since sensing takes place on the bitlines which divide cell charge by the cell to bitline capacitance ratio, much lower voltages than those in the cell are actually sensed. In a standard DRAM, these voltage differences are in the order of 100-300 mV. It is the voltage midpoints between these smaller signals that must finally be generated to allow for correct sensing.

Furuyama et al in the article noted above describes one method of sensing these voltages. Furuyama et al used three sense amplifiers and three approximate midpoint sensing voltages. The cell charge is shared with the bitline, the bitline is split into three sections (sub-bitlines) and three sense amplifiers determine whether the cell charge is above or below their particular reference voltages. This data is then converted to two bits and a resulting output. Reconversion of the two bits allows approximate values to be driven into the bitline so that restore takes place after the read cycle. A write cycle operates in the same way as the restore section of the read cycle.

It should be noted that since the cell shares charge with three sub-bitlines, and the reference cell with only one sub-bitline, the reference voltage is about three times larger than it should be for sensing, casting doubt on the operability of this design. Secondly, three sense amplifiers are used, and since sense amplifiers have been growing proportionally larger and larger with each generation of memory, a minimum of sense amplifiers is desirable. A third problem is that the reference voltage

is not stored on a cell whose [leakage does not] characteristics track the leakage of the data cells, introducing another source of error into the circuit.

SUMMARY OF THE PRESENT INVENTION

In the present invention a method and circuit has

been designed which substantially solves some of the above-identified problems. Only two sense amplifiers are required[, which generate the sensing voltages at the time of sensing]. In the present invention each bitline is split exactly in half, rather than into thirds, by use of a switch. The [noise margins are relatively large, equivalent to that of a standard DRAM maintaining reliability, and the] present design can be used as a standard one bit per cell DRAM as an alternative to a multiple bit per cell DRAM, which increases its universality, allows it to be used in present designs, and increases yield.

In accordance with an embodiment of the present invention, a method of processing data having one of four levels stored in a DRAM cell is comprised of sensing whether or not the data voltage is above or below a voltage level midway between a highest and a lowest of the four levels, setting the voltage on a reference line higher than the lowest and lower than the next highest of the four levels in the event the data voltage is below the midway voltage level, setting the voltage on the reference line higher than the second highest and lower than the highest of the four levels in the event the data

voltage is above the midway point, and sensing whether the data voltage is higher or lower in voltage than the reference line, whereby which of the four levels the data bit occupies is read.

In accordance with an embodiment of the present invention, a method of processing data having one of plural levels stored in a DRAM cell capacitor is comprised of dumping the charge of the cell capacitor on a first of a pair of conductors of a folded bitline, maintaining the other of the pair of conductors split into other sub-bitline conductors and charging each of the other sub-bitline conductors to an intermediate voltage, splitting the first of the conductors into first sub-bitline conductors, sensing the sub-bitlines to determine whether the charge of the cell has a higher voltage than the intermediate voltage of one of the other sub-bitline conductors and providing a logic level result signal, storing the logic level result signal in a dummy cell capacitor, setting a charge storage capacitor and all of the sub-bitlines other than the first sub-bitline maintaining a voltage resulting from the dumped charge to a predetermined voltage, dumping charge stored in the dummy cell capacitor on the sub-bitlines and charge storage capacitor, thereby varying the predetermined voltage stored thereon to a degree related to the capacities of the dummy cell capacitor, the charge storage cells and the predetermined voltage, to a level above or below the intermediate level, isolating the sub-bitlines, applying the intermediate voltage to one of the other sub-bitline conductors, comparing the cell voltage on one sub-bitline with the voltage on the other sub-bitline carrying the level above or below the intermediate level to obtain a first logic bit, and comparing the voltages carried by the other sub-bitlines to obtain a second logic bit, whereby the first and second logic bits are indicative of one of four logic states corresponding to one of the plural levels stored in the DRAM cell.

BRIEF INTRODUCTION TO THE DRAWINGS

A better understanding of the invention will be obtained by reference to the detailed description below, in conjunction with the following drawings, in which:

FIG. 1 is a diagram illustrating various voltage levels referred to in the description,

FIG. 2 is a block diagram used to illustrate the basic concepts of the invention,

FIG. 3 illustrates a block diagram in six steps of a read cycle,

FIG. 4 illustrates in block diagram two steps of a write or restore cycle,

FIG. 5 is a schematic diagram illustrating an embodiment of the invention, and

FIG. 6 illustrates a timing diagram of the schematic illustrated in FIG. 5.

DETAILED DESCRIPTION OF THE INVENTION

For a DRAM cell to store two bits using a single cell capacitor, the cell capacitor should store one of four voltage values V_{cell0} , V_{cell1} , V_{cell2} or V_{cell3} , wherein V_{cell0} represents the lowest and V_{cell3} represents the highest cell voltage. To differentiate between the voltages, mid-point voltages V_{ref1} , V_{ref2} and V_{ref3} are defined, as shown in FIG. 1. It may be seen that if the lowest actual cell voltage V_{cell0} is V_{SS} or zero, V_{ref1} is one-sixth the highest voltage V_{DD} , V_{cell1} is one-third V_{DD} , V_{ref2} is one-half V_{DD} , V_{cell2} is two-thirds V_{DD} , V_{ref3} is five-sixths V_{DD} and V_{cell3} equals V_{DD} . Thus it

may be seen that V_{ref1} is midway between V_{cell0} and V_{cell1} , V_{ref2} is midway between V_{cell0} and V_{cell3} and V_{ref3} is midway between V_{cell2} and V_{cell3} .

FIG. 2 will be used to illustrate the basic concept of the invention. A sense amplifier 1 can be connected to a pair of conductors 3A and 3B which form a folded bitline. Another sense amplifier 5 can be connected to a pair of conductors 7A and 7B which form the remainder of the folded bitline. In practice conductor 7A is a continuation of conductor 3A, and conductor 7B is a continuation of conductor 3B. The bitline is shown split in half as shown by dotted line 9. In practice, however, any of the sub-bitline conductors may be connected to any others, e.g. via FET switches.

Capacitor 11 represents a cell on which charge is stored in one of four voltage levels. It is desired to read the level and output two binary bits representing the charge level stored on capacitor 11.

The detailed sequence will be described below. It should be noted that sub-bitline conductor 7A can be brought to V_{ref2} , which is one-half V_{DD} . The voltage on sub-bitline 3B resulting from the charge stored on cell capacitor 11 is then compared with the voltage on conductor 7A to determine whether it is above or below V_{ref2} .

If the voltage on conductor 3B is above V_{ref2} , then the continuous conductor 3A-7B is brought to V_{ref3} , which is midway between the voltage level V_{cell2} and V_{cell3} . If the voltage on conductor 3B is below V_{ref2} , then the voltage on continuous conductor 3A, 7B is brought to V_{ref1} , which is midway between the V_{cell1} and V_{cell0} voltages. The continuous conductor 3A, 7B is referred to herein as a reference line.

It may be seen, therefore, that the voltage on the reference line is either above or below one-half V_{DD} , i.e. V_{ref2} , and is established midway between the only two voltages [Which] which conductor 3B can have, V_{cell0} and V_{cell1} , or V_{cell2} and V_{cell3} .

The voltage on sub-bitline 3B is then compared with the voltage on the reference line to determine whether it is above or below that voltage. If it is above that voltage the logic voltage must be either V_{cell1} or V_{cell3} ; whichever one it is, was established by the first determination of whether the voltage on conductor 3B was above or below the midway voltage V_{ref2} . Similarly if the voltage on conductor 3B is below the voltage on the reference line, the logic output represents either V_{cell0} or V_{cell2} , and again whichever one it is, was previously determined by the original determination of whether the voltage on conductor 3B is below or above V_{ref2} . In practice, the voltage on conductor 3B could be compared again [With] with V_{ref2} , which is on lead 7A, to select which of either of the two cell voltage possibilities should be selected.

The result is a two bit binary bit word representing which of the four charge levels is stored in capacitor 11.

FIG. 3 illustrates in more detail a sequence of the steps in the process. Consider first bitlines BL and BL*. These bitline references are not shown as such, but their connection points to a pair of sense amplifiers 13 and 15 are shown referenced BL and BL*. Sense amplifier 13 is provided to sense bit 0 and sense amplifier 15 is provided to sense bit 1. It is important that bitlines should be able to be split exactly in half, e.g. by apparatus such

as a switch into sub-bitline conductors [BLA, BLB, BL*A and BL*B.] BL_A, BL_B, BL_A* and BL_B*. The sense amplifiers can be enabled or disabled as required. Prior to step 1 all bitline segments are charged to the voltage V_{ref2} which is $\frac{1}{2} [V_{bb}] V_{dd}$.

In step 1, sub-bitlines BL_A and BL_B are disconnected from the V_{ref2} reference voltage, connected together and the sense amplifiers are not connected to the bitline. The cell capacitor 11 then dumps its charge onto the BL line formed of conductors BL_A and BL_B , resulting in a voltage which for example is

$$\left[\frac{V_{DD}}{2} + \frac{C_s(V_{cell2} - V_{REF2})}{C_s + C_{BL}} \text{ i.e. } \frac{V_{DD}}{2} + \frac{C_s}{C_s + C_{BL}} + \frac{2V_{DD}}{3} \right]$$

$$\frac{V_{DD}}{2} + \frac{C_s(V_{cell2} - V_{REF2})}{C_s + C_{BL}}$$

where C_s is the cell capacitance and C_{BL} is the capacitance of the entire bitline.

The voltage V_{ref2} which is $\frac{1}{2} V_{DD}$ is applied to the BL^* conductors BL_{A^*} and BL_{B^*} .

In step 2, the two halves of the BL conductor are separated, and the bit 1 sense amplifier is connected to sense the voltage on conductor BL_B to determine whether it is above or below the voltage V_{ref2} which is on the BL_{A^*} conductor. Since the voltage is V_{cell2} which is above V_{ref2} , a logic level one signal is stored in dummy cell 17 which is connected to the BL_B lead.

In step 3 the sense amplifier 15 and dummy cell 17 are disconnected from the bitline, and charge storage Ccell capacitor 18 is connected to lead BL_B . Conductors BL_B , BL_{B^*} , and BL_{A^*} are all connected together, and the midpoint voltage V_{ref2} is applied thereto.

In step 4 the logic level signal stored in dummy cell 17 is dumped to the sub-bitlines BL_B , BL_{B^*} and BL_{A^*} . The charge is also shared with Ccell 18, which has one half the capacitance of a normal cell. This charge sharing on the three half bitlines plus Ccell creates the exact reference level needed for the 2nd phase of sensing.

The total capacity of the Ccell 18 should be established so that the resulting voltage on the sub-bitlines is, in this example, V_{ref3} . Thus for example if the voltage on the Ccell and sub-bitlines was established at V_{ref2} , one-half V_{DD} in step 3, with the charge on dummy cell 17 having been established with full logic level V_{DD} in step 2, when it is connected to the combined sub-bitlines in step 4, its charge, being shared with the Ccell, should result in a voltage

$$\left(\frac{V_{DD}}{3} \right) \frac{C_s}{C_s + C_{BL}} + \frac{V_{DD}}{2}$$

i.e. V_{ref3} , which is midway between V_{cell2} and V_{cell3} .

On the other hand, if in step 2 the sensed bit was a zero, charge on dummy cell 17 would have been zero or V_{ss} . When connected to the combined bitlines in step 4 it would receive charge from the Ccell 18, causing a reduction in voltage to V_{ref1} , which is midway between V_{cell1} and V_{cell0} . Thus it may be seen that the combined sub-bitlines form a reference line, the voltage of which can be compared with that on cell 11, and corresponds to reference line 3A, 7B described with reference to FIG. 2.

In step 5 the Ccells 18 and dummy cell 17 are disconnected and each of the sub-bitlines are isolated. The voltage V_{ref2} of one-half V_{DD} is applied to the sub-bitline BL_{B^*} . It may be seen that the sub-bitline BL_{B^*} is now at the midpoint V_{ref2} , both sub-bitlines BL_{A^*} and BL_B are at the reference line voltage V_{ref3} (or V_{ref1} if the original cell voltage had been below V_{ref2}), and the sub-bitline [BLA] BL_A is at the cell capacitor 11 voltage.

The sense amplifiers 13 and 15 are then connected to their respective associated sub-bitlines. Bit zero from sub-bitlines BL^*_A and BL_A is sensed in sense amplifier 13, and preferably bit 1 from sub-bitline BL^*_B and BL_B is resensed. The outputs of the sense amplifiers 13 and 15 form a two bit binary word (bit 0 and bit 1) representing the level originally stored on cell 11.

FIG. 4 illustrates in steps 7 and 8 a write or restore operation.

Either immediately after step 6, for the restore operation, or at the beginning of a write operation, the sub-bitlines are separated and the sense amplifiers are disabled. In the case of a restore operation, the logic levels are already present on the sub-bitline conductors. In the case of a write operation, binary bits are written to each of the sub-bitline conductors, or to as many as are required to determine the level of the bit to be stored. To restore V_{cell0} or V_{cell3} the full logic level is left in the cell. To restore V_{cell1} or V_{cell2} the full logic level must be attenuated by $\frac{1}{2}$ as shown in the example step 8. In step 8, the required sub-bitlines BL^*_A , BL_A and BL_B shown are short-circuited together and the charge thereon is shared. This shared charge is written to cell capacitor 11 by connection of capacitor 11 thereto.

It should be noted that the concept described above has certain very significant advantages. For example no changes are required to either the currently used DRAM basic memory cell or to the DRAM manufacturing process.

Another advantage of this invention is that the first sensed step, i.e. step 2 of the read cycle described with reference to FIG. 3, can be simplified to appear identical to a standard one-bit-per-cell sense. If only the values 1,1 and 0,0 are stored in the cell, then the first sense has noise margins equal to $V_{DD}/2$, the same as a standard DRAM. Indeed, one step regenerative sensing is possible by allowing the sense amplifier to be enabled earlier in the operation and by not bothering to split the bitlines. Therefore if two bits per cell in the present design is not used, the memory wafers can still be used as standard one bit per cell structure. The resulting overhead to use the present invention is the extra sense amplifier, bitline splitting switches and cycle control logic. However the same design can be used for either one or two bits per cell application.

Reference is now made to FIGS. 5 and 6. In FIG. 5, a schematic-diagram of an embodiment of the present invention is shown. The convention is used of the bitline conductors referenced in FIG. 4, that is BL_A , BL^*_A , BL_B and BL^*_B . All of the transistors used in this embodiment are N channel field effect transistors (FETs). While steps 1-6 are described in detail, a person understanding the description below will be able to understand how the restore and write operations proceed without further explanation.

Conductors BL_A and BL_B and BL^*_A and BL^*_B are connected to respective source and drains of FET transistors 20 and 21 respectively, whose gates are driven by timing signals CB_L and CB_L^* respectively. Bitline conductor BL_B is connected to a terminal of sense amplifier 22 via the source-drain circuit of FET transistor 23, while bitline conductor BL_A is connected to sense amplifier 24 via FET 25. Similarly bitline conductor BL^*_B is connected to the other terminal of sense amplifier 22 via FET 26 and bitline conductor BL^*_A is connected to the other terminal of sense amplifier 24 via FET 27. FETs 23 and 26 are operated via a timing signal ISO2 which is applied to their gates, and FETs 25

and 27 are enabled by timing signal ISO1 applied to their gates.

Bitline precharge voltage V_{BLP} is applied to bitlines BL_A and BL_A^* via FETs 28 and 29, and to bitline conductors BL_B and BL_B^* via FETs 30 and 31.

The charge to be sensed is stored on cell capacitor 32, which is connected to bitline BL_A via FET 33, which is driven by the timing signal WL1 received from a word line applied to its gate.

In operation, initially the bitline portions are isolated from each other by the C_{BL} and C_{BL}^* timing voltage being low rendering FETs 20 and 21 non-conductive, and precharge voltage is applied to the four bitline conductors via transistors 28, 29, 30 and 31 due to timing voltages M_{A1} , M_{A1^*} , M_{A2} and M_{A2^*} being high. At the same time the bitline conductor voltages are equalized via FETs 39 and 34 short-circuiting bitline conductor pairs BL_A and BL_A^* , and BL_B and BL_B^* respectively, FET 39 being enabled by the E_{Q1} timing voltage being applied to its gate, FET 34 being enabled by E_{Q2} .

Once precharge has been completed, the timing voltages E_{Q1} , E_{Q2} and M_{A1} , M_{A2} and M_{A2^*} go low, causing transistors 39, 34, 29, 31 and 30 to open. Timing voltage M_{A1^*} remains high, maintaining precharge voltage (V_{ref2} in step 1 of FIG. 3) on bitline conductor $[B_{L^*A}] \underline{BL}_A^*$.

The next step is for the timing voltage C_{BL} to go high for a short interval and at the same time for WL_1 to go high. This causes FET 20 to conduct, connecting bitline conductors BL_A and BL_B together, and at the same time transistor 33 conducts, causing the charge from bit storage capacitor 32 to be dumped to the bitline conductor BL_A . Since the timing voltages ISO1 and ISO2 are low, the transistors 25, 27, 23 and 26 are open, isolating the sense amplifiers 24 and 22 from the bitlines. The stage of step 1 in which the cell charge from capacitor 32 is dumped onto the bitline conductors BL_A and BL_B and that the remaining bitline conductors BL_A^* and BL_B^* have been precharged to a midpoint reference voltage $V_{BLP}(V_{ref2})$ has thus been completed.

Once the charge has been dumped onto the bitline, the C_{BL} timing voltage returns to a low level, isolating the bitline conductors BL_A and BL_B and following this the ISO2 voltage goes high, enabling transistors 23 and 26. The timing voltages V_{S2} and V_{R2} flip, causing sense amplifier 22 to sense the bit stored on bitline conductor $[B_{L_B}] \underline{BL}_B$ relative to the midpoint reference voltage stored on

bitline $[B_{L^*B}] \underline{BL}_B^*$. The full logic level value of the sensed bit

(0 or 1) is then applied by sense amplifier 22 to the bitline. Timing voltage WL_2 going high enables FET 35, causing the sensed bit logic level voltage to be stored in dummy capacitor cell 36.

The timing voltage WL_2 then drops, isolating capacitor 36. The voltages V_{S1} and V_{S2} applied to sense amplifier 22 reverse, disabling sense amplifier 22. This completes step 2, wherein the bit has been sensed and stored in the dummy cell capacitor 36.

The timing voltage ISO2 then drops, causing transistors 23 and 26 to isolate the bitline conductors BL_B and BL_B^* from sense amplifier 22. The timing voltages E_{Q2} , M_{A2} and M_{A2^*} then go high, causing transistor 34 to conduct and short-circuiting bitline conductors BL_B and BL_B^* , and causing FETs 31 and 30 to conduct, allowing reference voltage $V_{BLP}(V_{ref2})$ to be reapplied to the bitline conductors BL_B and BL_B^* . Then the timing voltage C_{BL}^* goes high, causing transistor 21 to conduct, joining bitline conductors BL_A^* with BL_B and BL_B^* . Accordingly the reference voltage V_{BLP} is applied to those three bitline conductors, which are equalized.

Ccell capacitor 37 is then connected to the bitline conductor BL_B via FET 38 due to the gate of FET 38 going high with the timing voltage V_{CL} . This completes operation through to the completion of step 3 described with reference to FIG. 3.

The timing voltage M_{42} and M_{42^*} , as well as M_{41} , then go to low level, inhibiting FETs 31, 30 and 28, cutting off reference voltage V_{BLP} from the bitline conductors.

The next step is for the timing voltage $WL2$ to go high. This causes the charge stored on dummy cell capacitor 36 to be dumped onto the three interconnected bitline conductors BL_B , BL_{A^*} and BL_A , and as well onto Ccell 37. This completes step 4 described with reference to FIG. 3.

The timing voltage $EQ2$ then drops to low level, removing the short circuit between the bitline conductors BL_B and BL_{A^*} , and the timing voltage C_{BL^*} drops to low level, causing separation of the bitline conductors BL_{A^*} and BL_B . The four bitline conductors are thus mutually isolated.

The timing voltage M_{42^*} then goes to high level for a short period, recharging the bitline conductor $[BL_B] BL_{B^*}$ to the reference voltage V_{BLP} . The result, at this stage, is that the bitline conductor $[BL_B] BL_{B^*}$ is at the voltage of reference level V_{BLP} , the bitline conductors $[BL_A] BL_{A^*}$ and BL_B are charged to the distributed level resulting from the charge previously stored on dummy capacitor 36, and the bitline conductor $[BL_A] BL_A$ is charged to the level stored on the bit storage cell capacitor 32. This completes step 5 described with reference to FIG. 3.

The timing voltages ISO1 and ISO2 then go to high level, enabling FETs 23 and 26, and 25 and 27, thus connecting sense amplifiers 22 and 24 to the bitlines. The timing voltages V_{S1} and V_{S2} and V_{R1} and V_{R2} are inverted, causing operation of sense amplifiers 22 and 24, thus sensing the bit stored on the two bitlines BL_A and BL_{A^*} relative to the voltages (which are at the same voltage level) on bitline conductors BL_{A^*} and BL_B . This completes the operation of step 6 described with reference to FIG. 3.

The output result of sense amplifier 22 and 24 are thus two bits which describe the charge level stored in capacitor 32 to the accuracy of $2^2=4$ levels, as described above.

It should be noted that there are several ways of expanding the above invention so that more than four charge levels stored on bit storage capacitor 32 can be detected. One way is to use a variable reference voltage V_{BLP} , which is changed in the direction of the sensed bit level following either a first or successive sensing steps. A second way is to use more than the three voltage reference levels $1/6 V_{DD}$, $1/3 V_{DD}$, and $5/6 V_{DD}$ described. The bitlines may be divided into three sections for three successive sensing operations to get 8 levels, 4 sections [or] 16 levels, etc. By successive sensing and charge juggling between the dummy capacitor and Ccell capacitors, first coarse and then finely tuned, voltage references can be established, following which the sensing of the charge in the memory cell can be effected as being either above or below the established voltage reference.

A person understanding this invention may now conceive of alternative structures and embodiments or variations of the above. All of those which fall within the scope of the claims appended hereto are considered to be part of the present invention.

I claim:

1. A method of processing data having one of four voltage levels stored in a DRAM cell comprising:

- (a) sensing whether or not the data voltage is above or below a voltage level midway between a highest and a lowest of said four levels,
- (b) setting the voltage on a reference line higher than the lowest and lower than the next highest of said four levels in the event the data voltage is below said midway voltage level, and setting the voltage on the reference line higher than the second highest and lower than the highest of said four levels in the event the data voltage is above said midway voltage level, and
- (c) sensing whether the data voltage is higher or lower than the reference line, whereby which of the four levels the data occupies is read.

2. A method as defined in claim 1 in which the voltage on the reference line is set at approximately one half the voltage difference between either of the lowest or highest voltage level and the adjacent one of the four voltage levels.

3. A method as defined in claim 1 in which said four levels are at 0, $\frac{1}{3}$, $\frac{2}{3}$ and 1 times a power supply voltage scaled by the cell to bitline capacitance ratio, and in which the voltage on the reference line in step (b) is set at either $1/6$ or $5/6$ the power supply voltage in step (b) scaled by the cell to bitline capacitance ratio.

4. A method as defined in claim 1 including charging a dummy capacitor to a level representing whether or not said data is above or below said midway voltage, and setting the voltage on the reference line by establishing a voltage level thereon which is midway between the highest and lowest of said four levels, then raising or lowering the voltage level thereon by dumping the charge from said dummy capacitor thereon.

5. A method of processing data having one of plural levels stored in a DRAM cell capacitor comprising:

- (a) dumping the charge of the cell capacitor on a first conductor of a pair of conductors of a folded bitline,
- (b) maintaining the other conductor of said pair of conductors split into other sub-bitline conductors and charging each of said other sub-bitline conductors to an intermediate voltage,
- (c) splitting said first of said pair of conductors into first sub-bitline conductors,
- (d) sensing one of said sub-bitline conductors to determine whether the charge of said cell has a higher voltage than the intermediate voltage of one of said

other sub-bitline conductors and providing a logic level result signal.

- (e) storing said logic level result signal in a dummy cell capacitor,
- (f) setting a charge storage capacitor and all of the sub-bitlines other than a first sub-bitline conductor on which the charges of cell capacitor was dumped, at to a predetermined voltage,
- (g) dumping charge stored in the dummy cell capacitor on said sub-bitlines conductors other than the first sub-bitline conductor to which the charge of the cell capacitor was dumped, and on said charge storage capacitor together, thereby varying the predetermined voltage stored thereon to a degree related to the capacities of said dummy cell capacitor, said charge storage capacitor and said predetermined voltage, to a level above or below the intermediate level,
- (h) isolating the sub-bitlines,
- (i) applying said intermediate voltage to one of said other sub-bitline conductors,
- (j) comparing the cell voltage on one sub-bitline with the voltage on said other sub-bitline carrying said level above or below the intermediate level to obtain a first logic bit, and comparing the voltages carried by the other sub-bitlines to obtain a second logic bit,

whereby said first and second logic bits are indicative of one of four states corresponding to one of said plural levels stored in the DRAM cell.]

[6. A method as defined in claim 5 in which said intermediate and said predetermined voltages are the same.]

[7. A method as defined in claim 6 in which said intermediate and predetermined voltages are the same mid-point voltage between a highest and lowest voltage state representative of four logical states.]

[8. A method as defined in claim 7, including the further steps of short circuiting two or three of the sub-bitlines to share charge thereon and establish a common voltage level, and storing said shared charge corresponding to the common voltage level on said cell, whereby a restore or write operation results.]

[9. A method as defined in claim 7, including the further steps of writing logic voltage levels to each of the sub-bitline conductors, short circuiting two or three of the sub-bitlines to share charge thereon and establish a common voltage level, and storing said shared charge corresponding to the common voltage level on said cell, whereby a write operation results.]

* * * *

10. A method for storing a multi-bit value in a DRAM cell, the method comprising:
storing a charge in a cell capacitor, the stored charge producing one of a plurality of data voltage values;
precharging subbitlines of a pair of bitlines to one of a plurality of predetermined reference voltage levels;
dumping the stored charge onto a precharged subbitline of at least one pair of subbitlines to produce a sensing voltage;
determining a bit of the multi-bit value by comparing the sensing voltage to the reference voltage;
for each additional bit,
adjusting the reference voltage responsive to last determined bit; and
determining the additional bit by comparing the sensing voltage to the adjusted reference voltage.
11. The method of Claim 10, wherein adjusting the reference voltage comprises:
storing a charge in a dummy capacitor, said charge being indicative of previously determined bits;
charging at least one second cell capacitor to a reference voltage; and
dumping the charge stored in the dummy capacitor onto a plurality of subbitlines, and sharing said charge with the at least one second cell capacitor, the at least one second cell capacitor having a capacitance such that the adjusted reference voltage is established, said adjusted reference voltage being one of the plurality of predetermined reference voltage levels
12. The method of Claim 10, wherein the pair of bitlines is divided into a number of subbitlines, said number responsive to the number of data voltage values.
13. The method of Claim 10, wherein the DRAM cell is capable of operating in either of two modes, a first mode being as a one bit per cell DRAM, and a second mode being as a multibit per cell DRAM.
14. The method of Claim 10, wherein adjusting the reference voltage is in the direction of a last sensed bit.
15. A multi-bit DRAM cell, comprising:
a cell capacitor in which one of a plurality of voltage values is maintained;
means for precharging subbitlines of a pair of bitlines, the pair of bitlines being subdivided into a plurality of subbitlines
a plurality of switches for interconnecting the subbitlines;
a plurality of sensing amplifiers, each sensing amplifier associated with and switchably connected to a pair of subbitlines;
means for dumping the stored charge onto a precharged subbitline of at least one pair of subbitlines to produce a sensing voltage; and
means for adjusting the reference voltage responsive to a last determined bit.

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16. The multi-bit DRAM cell of Claim 15, wherein switches are FET switches.
 17. The multi-bit DRAM cell of Claim 16, wherein means for adjusting the reference voltage comprises:
 a dummy capacitor, in which a charge indicative of previously determined bits is stored; and
 at least one second cell capacitor having a capacitance such that upon dumping the charge stored in the dummy capacitor into said at least one second cell capacitor, the adjusted reference voltage is established, said adjusted reference voltage being one of the plurality of predetermined reference voltage levels.
 18. The multi-bit DRAM cell of Claim 16, wherein the pair of bitlines is divided into a number of subbitlines, said number responsive to the number of data voltage values.
 19. The multi-bit DRAM cell of Claim 16, wherein the DRAM cell is capable of operating in either of two modes, a first mode being as a one bit per cell DRAM, and a second mode being as a multibit per cell DRAM.

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ABSTRACT

A method of processing data having one of four voltage levels stored in a DRAM cell is comprised of sensing whether or not the data voltage is above or below a voltage level midway between a highest and a lowest of the four levels, setting the voltage on a reference line higher than the lowest and lower than the next highest of the four levels in the event the data voltage is below the midway voltage level, and setting the voltage on the reference line higher than the second highest and lower than the highest of the four levels in the event the data voltage is above the midway point, and sensing whether the data voltage is higher or lower than the reference line, whereby which of the four levels the data occupies is read.

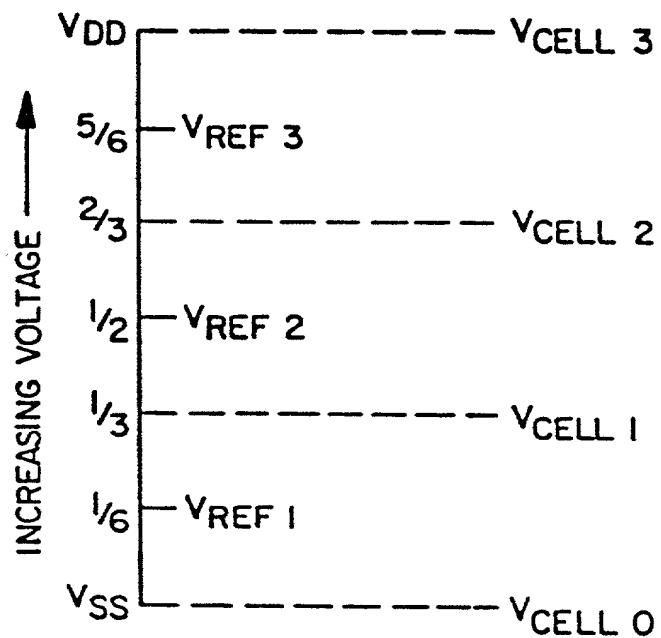


FIG. 1

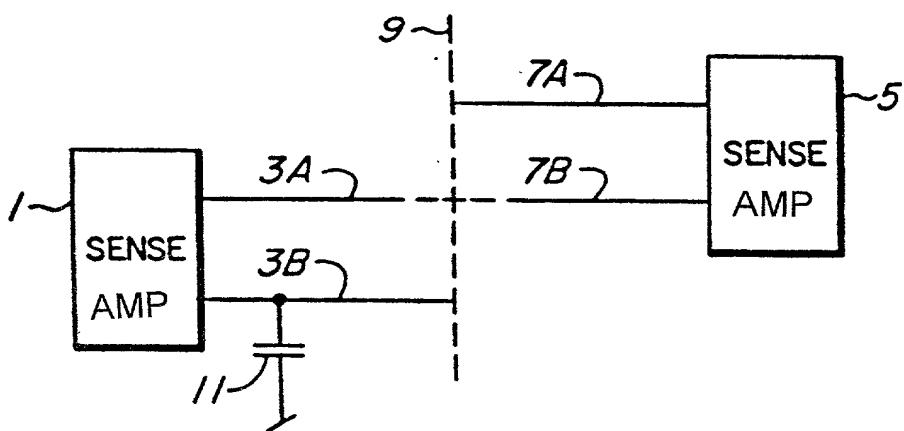


FIG. 2

FIG. 3

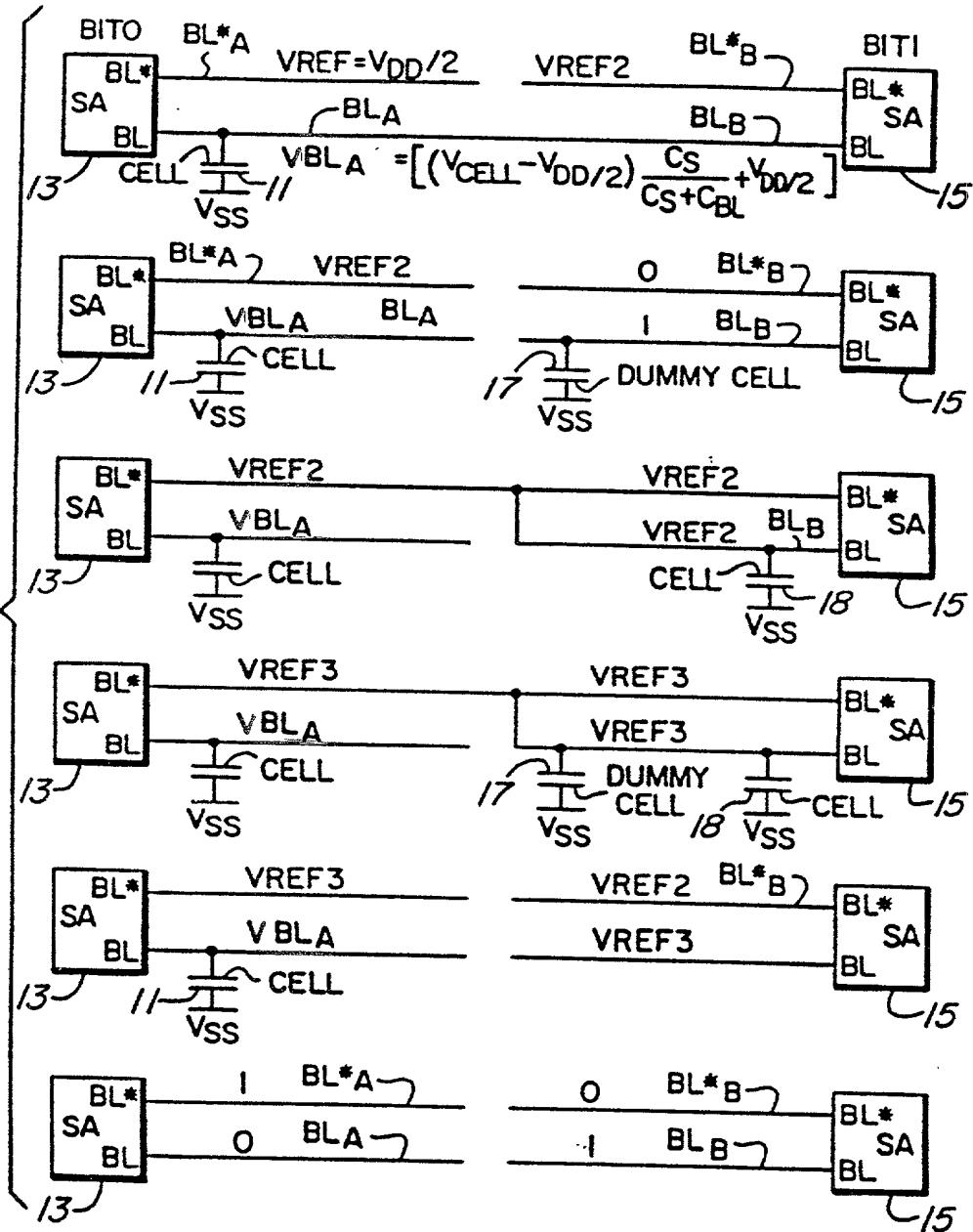
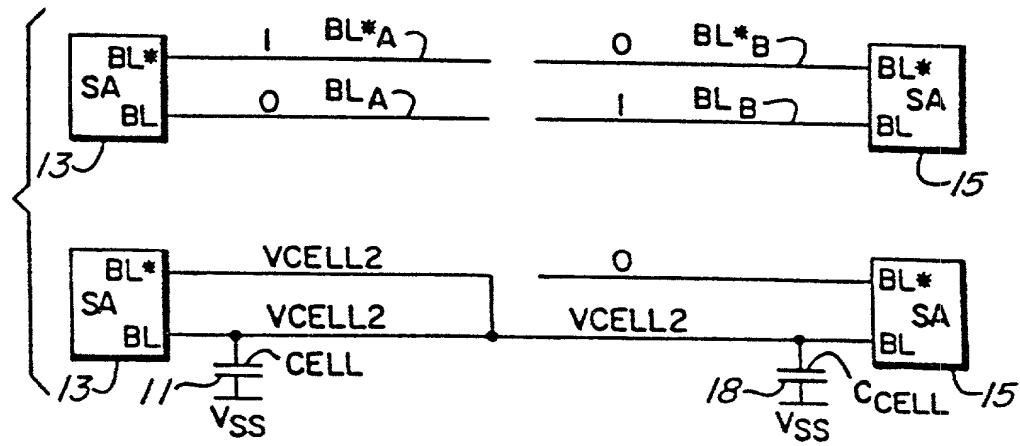


FIG. 4



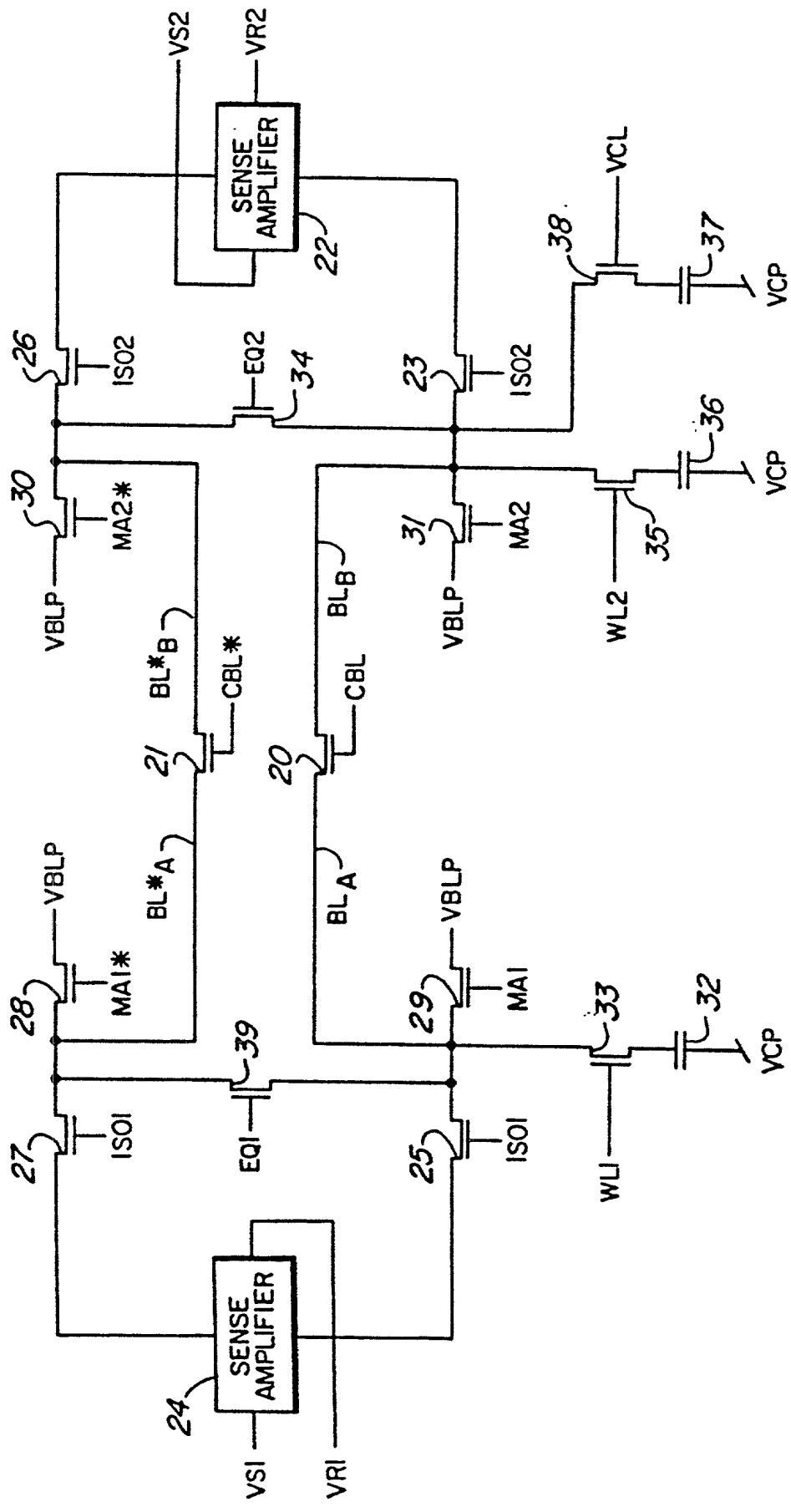


FIG. 5

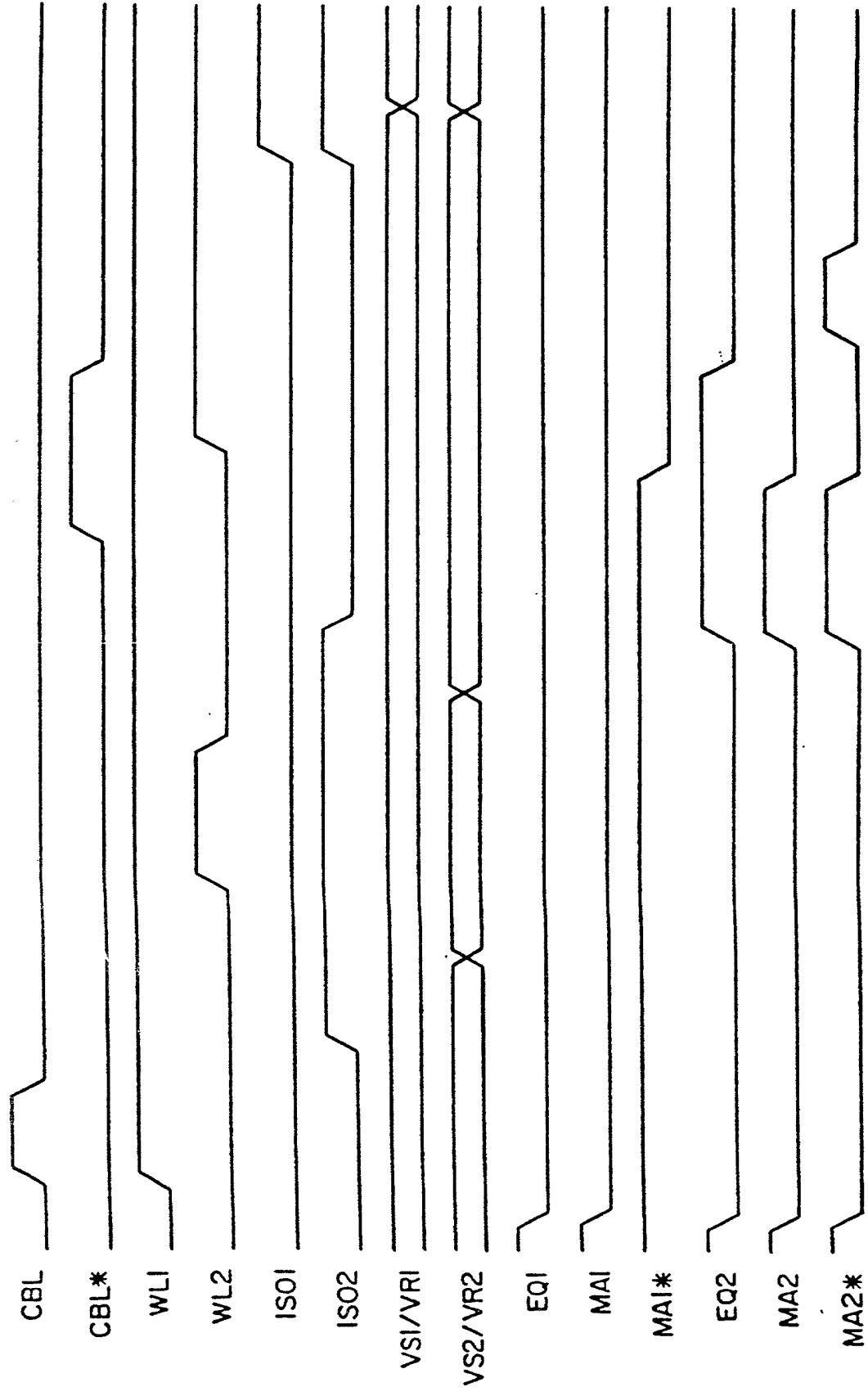


FIG. 6

:ODMAIMHODMAIMManage;139772;1

JMS/GMB/dlc

August 16, 2000

PATENT APPLICATION
Docket No.: 2037.1005-002**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Peter B. Gillingham

Reissue Application of U.S. Patent 5,283,761, Issued February 1, 1994

For: METHOD OF MULTI-LEVEL STORAGE IN DRAM AND APPARATUS
THEREOF (as amended)Date: 8-29-00EXPRESS MAIL LABEL NO. EL551544795US**DECLARATION AND POWER OF ATTORNEY**
FOR CONTINUATION OF REISSUE PATENT APPLICATIONThe Assistant Commissioner
for Patents
Washington, DC 20231

Sir:

As inventor of U.S. Patent No. 5,283,761, I hereby declare that:

1. My residence, post office address and citizenship are stated below next to my name.
2. I believe that I am the first and original inventor of the claimed subject matter described in United States Patent No. 5,283,761 granted on February 1, 1994 (hereinafter the '761 patent) entitled METHOD OF MULTI-LEVEL STORAGE IN DRAM for which a reissue patent is sought.

08/595,020

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3. I have reviewed and I understand the contents of the specification of the subject reissue application, including the claims.
4. I hereby claim the benefit under 35 U.S.C. 120 of any United States application(s), or 365(c) of any PCT international application designating the United States of America, listed below and, insofar as the subject matter of each of the claims of this application is not disclosed in the prior United States or PCT International application in the manner provided by the first paragraph of 35 U.S.C. 112, I acknowledge the duty to disclose information known by me to be material to patentability as defined in 37 C.F.R. 1.56 which became available between the filing date of the prior application and the national or PCT international filing date of this application:

(Application Serial No.)	(Filing date)	(Status: patented, pending, abandoned)
<u>08/595,020</u>	<u>January 31, 1996</u>	<u>Pending (Allowed)</u>

5. I believe the original '761 patent is wholly or partly inoperative or invalid by reason of my claiming less than I had a right to claim in the patent.
6. One error being relied upon as a basis for reissue is that the original claims 1-9 failed to claim an embodiment in which a DRAM cell is capable of operating as either a one-bit-per-cell DRAM or as a multi-bit-per-cell DRAM, as disclosed in the original '761 patent at column 2, lines 54-56.
7. All errors being corrected in the reissue application, including all amendments up to the time of and with the filing of this Declaration, arose without any deceptive intention on the part of the applicant.

08/595,020

-3-

8. As a named inventor, I hereby appoint the attorneys and/or agents associated with

**Hamilton, Brook, Smith & Reynolds, P.C., Two Militia Drive,
Lexington, Massachusetts 02421-4799 - Customer No. 21005,**

to prosecute this application and to transact all business in the Patent and Trademark Office connected therewith.

Please send correspondence to:

Customer No. 21005

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Direct telephone calls to: Mary Lou Wakimura, Telephone No.: 781-861-6240

Direct facsimiles to: Mary Lou Wakimura, Telephone No. 781-861-9540

08/595,020

-4-

9. I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

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Date: 21 August 2000

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Citizenship: Canadian

Post Office Address: 43 Slade Crescent
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CERTIFICATE UNDER 37 C.F.R. § 3.73(b)Applicant(s): Peter B. GillinghamApplication No.: 08/595,020Filed: January 31, 1996For: METHOD OF MULTI-LEVEL STORAGE IN DRAM AND APPARATUS THEREOF (as amended)

16639 U.S. PRO
09/654367
09/01/00

MOSAID TECHNOLOGIES INCORPORATED

(Name of Assignee)

, a corporation

(Type of Assignee, e.g., corporation, partnership, university, government agency, etc.)

certifies that it is

- A. the assignee of the entire right, title and interest in the patent application identified above.
- B. an assignee together with [] of the entire right, title and interest in the patent application identified above. A separate Certificate under 37 CFR § 3.73(b) is attached.

The right, title and interest of the above-named assignee in the patent application identified above is established by virtue of:

- A. An assignment from the inventor(s) of the patent application identified above. The assignment was recorded in the Patent and Trademark Office at Reel 6207, Frame 647, or for which a copy thereof is attached.

OR

- B. A chain of title from the inventor(s) of the patent application identified above, to the current assignee as shown below:

1. From: _____ To: _____
The document was recorded in the Patent and Trademark Office at Reel _____, Frame _____, or for which a copy thereof is attached.
2. From: _____ To: _____
The document was recorded in the Patent and Trademark Office at Reel _____, Frame _____, or for which a copy thereof is attached.
3. From: _____ To: _____
The document was recorded in the Patent and Trademark Office at Reel _____, Frame _____, or for which a copy thereof is attached.

 Additional documents in the chain of title are attached. Copies of assignments or other documents in the chain of title are attached.

The undersigned (whose title is supplied below) is empowered to act on behalf of the assignee.

I hereby declare that all statements made herein of my own knowledge are true, and that all statements made on information and belief are believed to be true; and further, that these statements are made with the knowledge that willful false statements and the like so made, are punishable by fine or imprisonment, or both, under Section 1001, Title 18 of the United States code, and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

Date: 21 August 2000Name: George Cwynar Peter GillinghamTitle: President VP Business DevelopmentSignature: Peter Gillingham